

April 2000

FQP3P20

200V P-Channel MOSFET

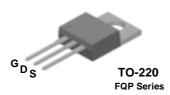
General Description

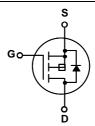
These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters.

Features

- -2.8A, -200V, $R_{DS(on)}$ = 2.7 Ω @V_{GS} = -10 V Low gate charge (typical 6.0 nC)
- Low Crss (typical 7.5 pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQP3P20	Units
V _{DSS}	Drain-Source Voltage		-200	V
I _D	Drain Current - Continuous (T _C = 25°	C)	-2.8	А
	- Continuous (T _C = 100°C)		-1.77	А
I _{DM}	Drain Current - Pulsed	(Note 1)	-11.2	А
V_{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	150	mJ
I _{AR}	Avalanche Current	(Note 1)	-2.8	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	5.2	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-5.5	V/ns
P_D	Power Dissipation (T _C = 25°C)		52	W
	- Derate above 25°C		0.42	W/°C
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.4	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-200			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-0.18		V/°C
I _{DSS} Zero (Zana Cata Valtana Busin Course	V _{DS} = -200 V, V _{GS} = 0 V			-1	μА
	Zero Gate Voltage Drain Current	V _{DS} = -160 V, T _C = 125°C			-10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
On Cha	aracteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-3.0		-5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -1.4 A		2.06	2.7	Ω
g _{FS}	Forward Transconductance	$V_{DS} = -40 \text{ V}, I_{D} = -1.4 \text{ A}$ (Note 4)		1.23		S
C _{iss}	Input Capacitance Output Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		190 45	250 60	pF pF
C _{rss}	Reverse Transfer Capacitance			7.5	10	pF
Switch	ing Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = -100 V, I _D = -2.8 A,		8.5	25	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		35	80	ns
t _{d(off)}	Turn-Off Delay Time			12	35	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		25	60	ns
•				6.0	8.0	nC
Q _g	Total Gate Charge	$V_{DS} = -160 \text{ V}, I_{D} = -2.8 \text{ A},$		0.0	0.0	110
Q _g	Total Gate Charge Gate-Source Charge	$V_{DS} = -160 \text{ V}, I_{D} = -2.8 \text{ A},$ $V_{GS} = -10 \text{ V}$		1.7		nC
Q _g Q _{gs} Q _{gd}	· · ·					_
Q _g Q _{gs} Q _{gd}	Gate-Source Charge Gate-Drain Charge	V _{GS} = -10 V (Note 4, 5)		1.7		nC
Q _g Q _{gs} Q _{gd} Drain-S	Gate-Source Charge	$V_{GS} = -10 \text{ V}$ (Note 4, 5)		1.7		nC
Q_g Q_{gs} Q_{gd} Drain-S	Gate-Source Charge Gate-Drain Charge Source Diode Characteristics are	V _{GS} = -10 V (Note 4, 5) nd Maximum Ratings ode Forward Current		1.7		nC nC
Q _g Q _{gs} Q _{gd} Drain-S	Gate-Source Charge Gate-Drain Charge Source Diode Characteristics as Maximum Continuous Drain-Source Dio	V _{GS} = -10 V (Note 4, 5) nd Maximum Ratings ode Forward Current		1.7 2.9	-2.8	nC nC
Q_g Q_{gs} Q_{gd} Drain-S	Gate-Source Charge Gate-Drain Charge Source Diode Characteristics as Maximum Continuous Drain-Source Diode Maximum Pulsed Drain-Source Diode F	V _{GS} = -10 V (Note 4, 5) nd Maximum Ratings ode Forward Current Forward Current		1.7 2.9	 -2.8 -11.2	nC nC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 29mH, I_{AS} = -2.8A, V_{DD} = -50V, R_G = 25 Ω. Starting T_J = 25°C 3. I_{SD} ≤ -2.8A, di/dt ≤ 300Α/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

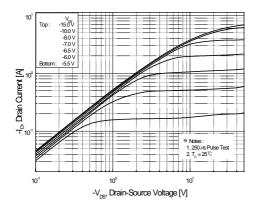
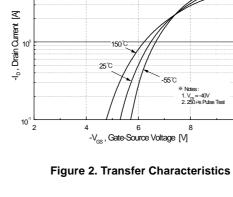


Figure 1. On-Region Characteristics



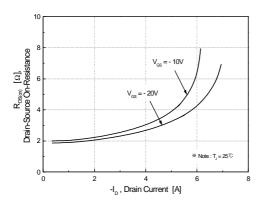


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

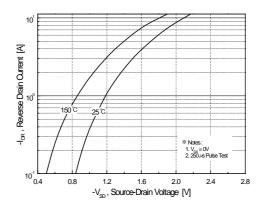


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

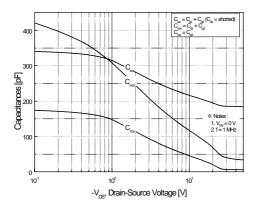


Figure 5. Capacitance Characteristics

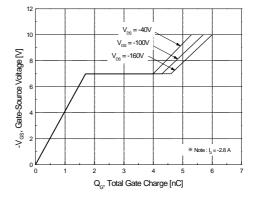


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

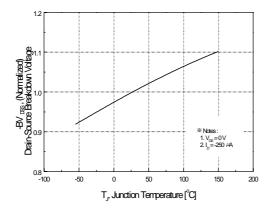


Figure 7. Breakdown Voltage Variation vs. Temperature

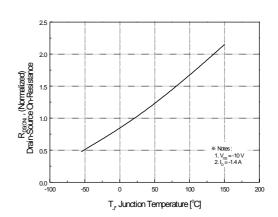


Figure 8. On-Resistance Variation vs. Temperature

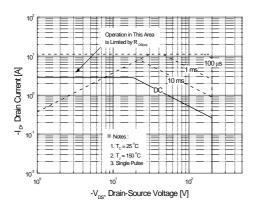


Figure 9. Maximum Safe Operating Area

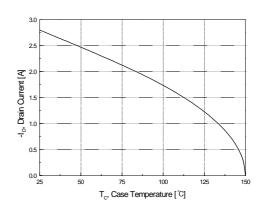


Figure 10. Maximum Drain Current vs. Case Temperature

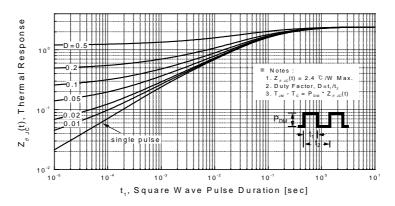
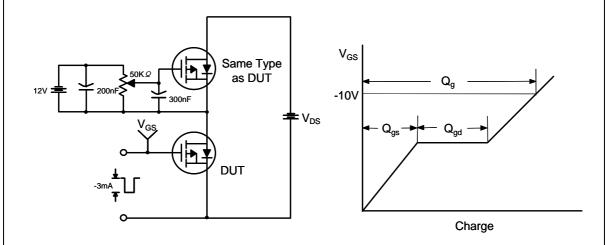


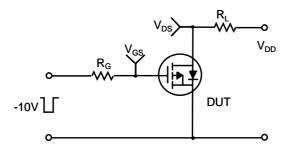
Figure 11. Transient Thermal Response Curve

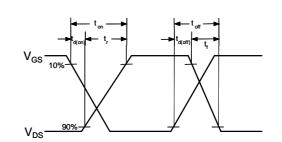
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Gate Charge Test Circuit & Waveform

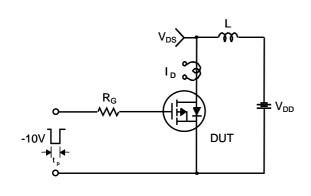


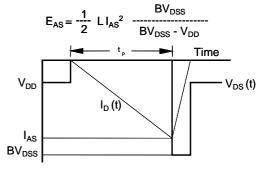
Resistive Switching Test Circuit & Waveforms



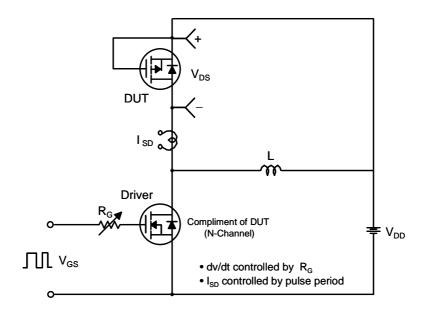


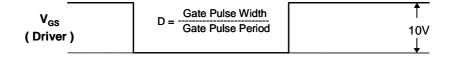
Unclamped Inductive Switching Test Circuit & Waveforms

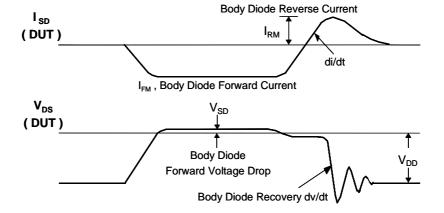


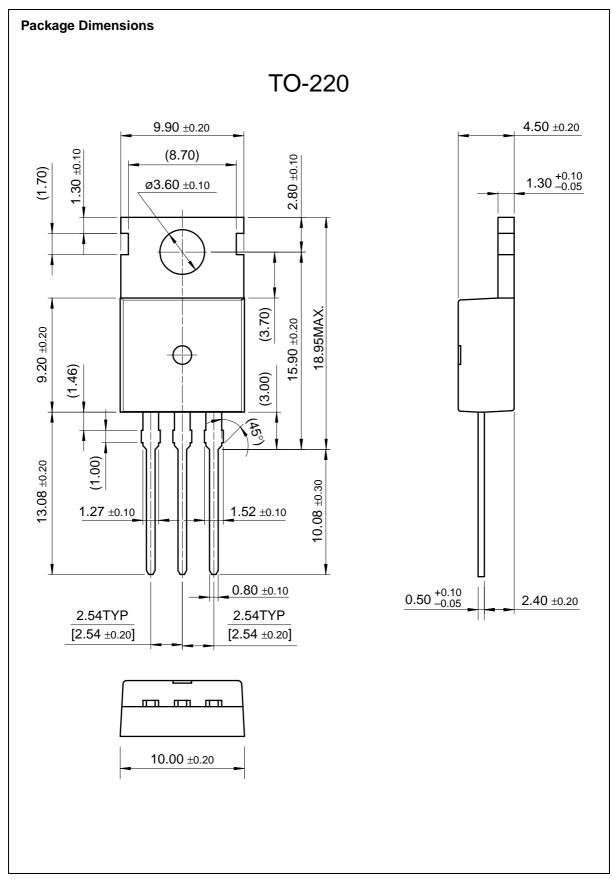


Peak Diode Recovery dv/dt Test Circuit & Waveforms









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